



AIGROW: A Feedback-Driven Test Generation Framework for Hardware Model Checkers

Wenjing Deng

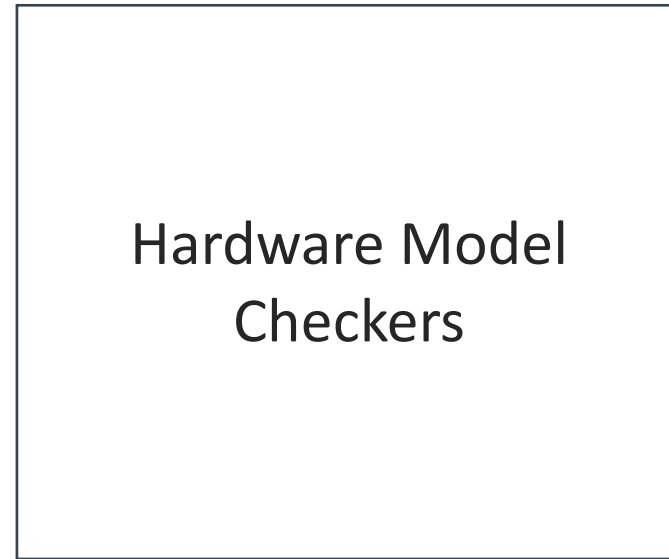
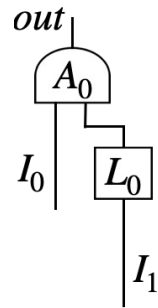
Shanghai Key Laboratory of Trustworthy Computing
East China Normal University, China

Hardware Model Checkers

the tools for validating the implementation of hardware designs

property →
out != True

design →



→ unsatisfied

Determine whether the
design satisfies the property.

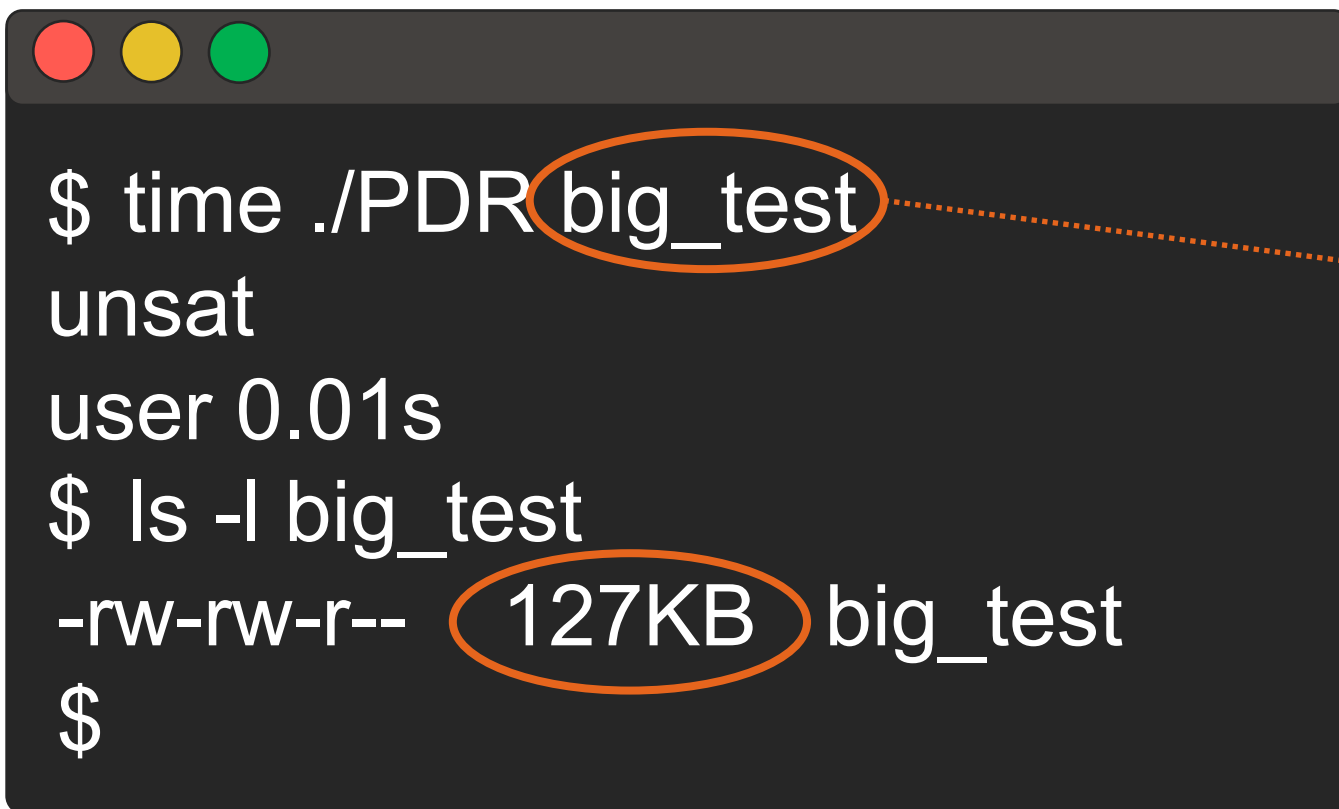
Hardware Model Checkers

the tools for validating the implementation of hardware designs

They should be intensively **evaluated!**

Hardware Model Checkers

PDR: a mature hardware model checker

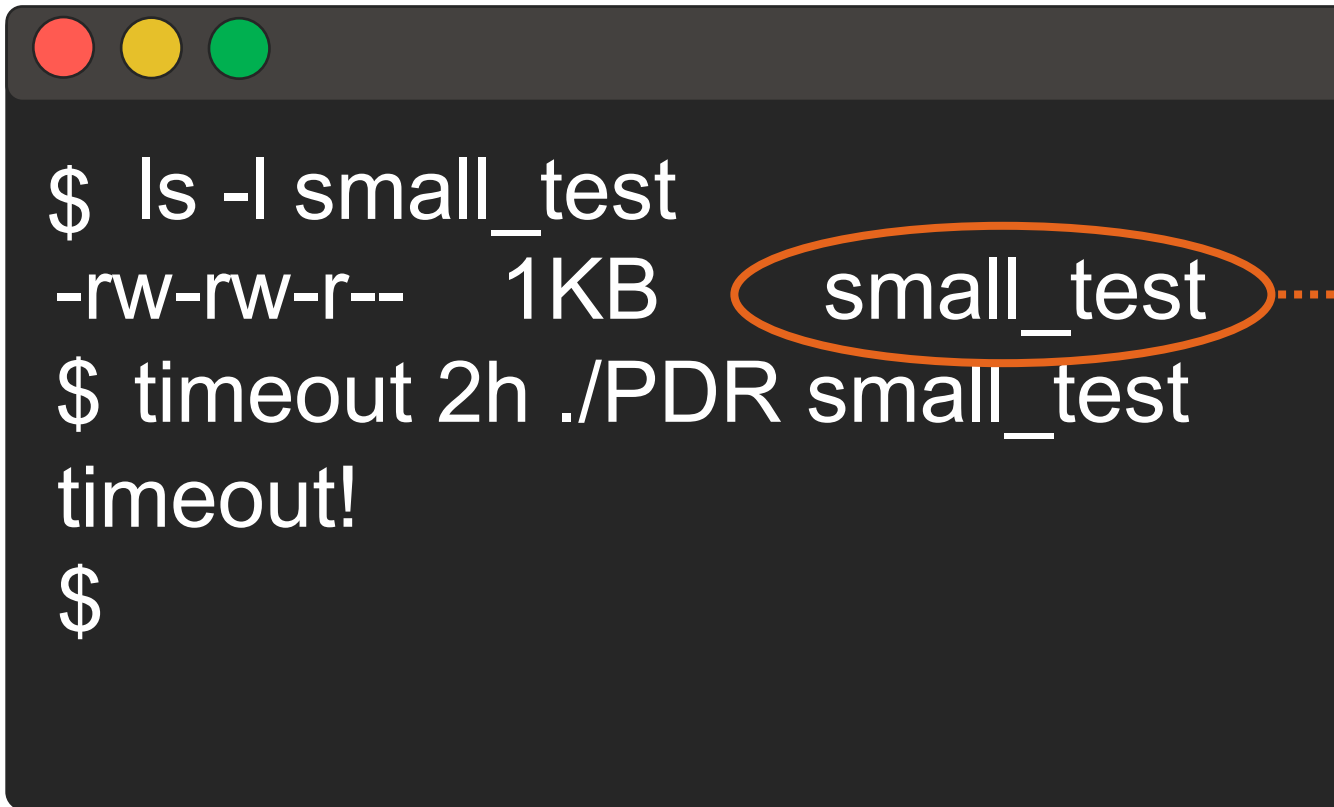


```
$ time ./PDR big_test
unsat
user 0.01s
$ ls -l big_test
-rw-rw-r-- 127KB big_test
$
```

From Intel.zip

Hardware Model Checkers

PDR: a mature hardware model checker



```
$ ls -l small_test
-rw-rw-r-- 1KB small_test
$ timeout 2h ./PDR small_test
timeout!
$
```

High-quality test

Difficult

Small size

Diverse

Hard to obtain!

Introduction

Why high-quality tests are hard to obtain?

| Source of Tests | Availability | Difficulty | Avg. size | Diversity |
|-----------------------|--------------|------------|-----------|-----------|
| Real world benchmarks | no | yes | large | high |
| generation tools | | | | |
| Our approach | - | - | - | - |

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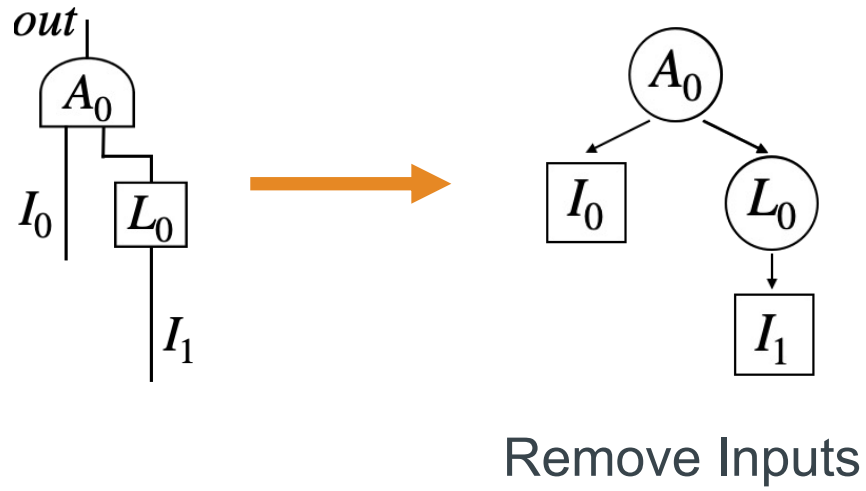
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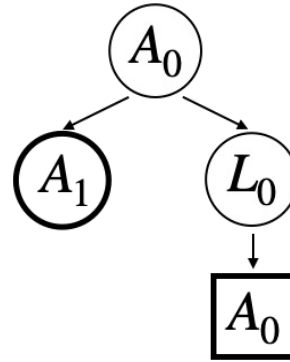
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Our approach is to **incrementally generate** tests with **feedback**.

Our Approach: Incremental Generation

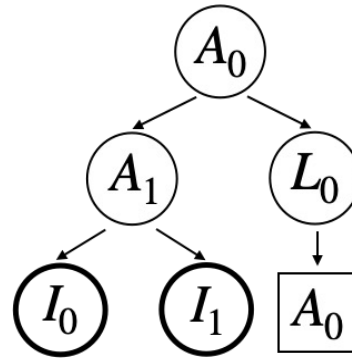


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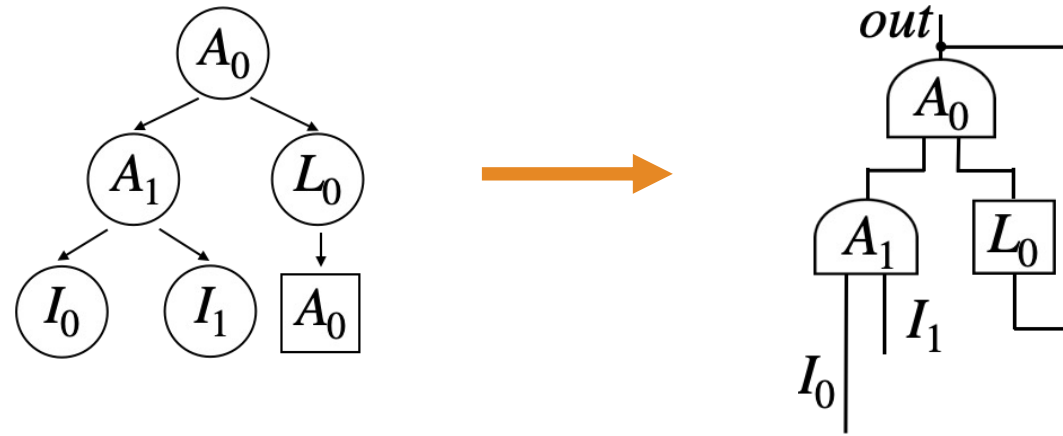
Add Nodes

Our Approach: Incremental Generation

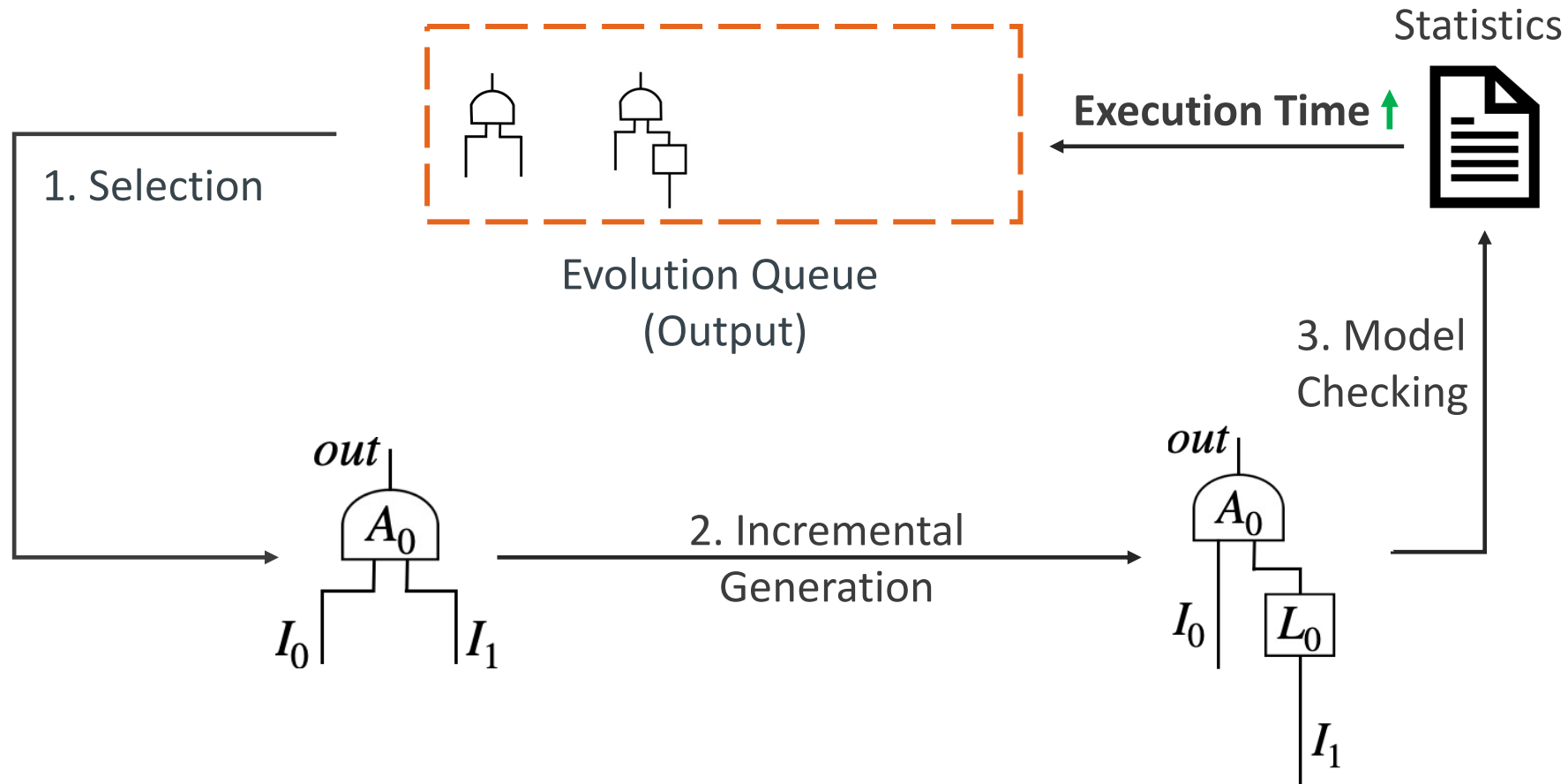


Add Inputs

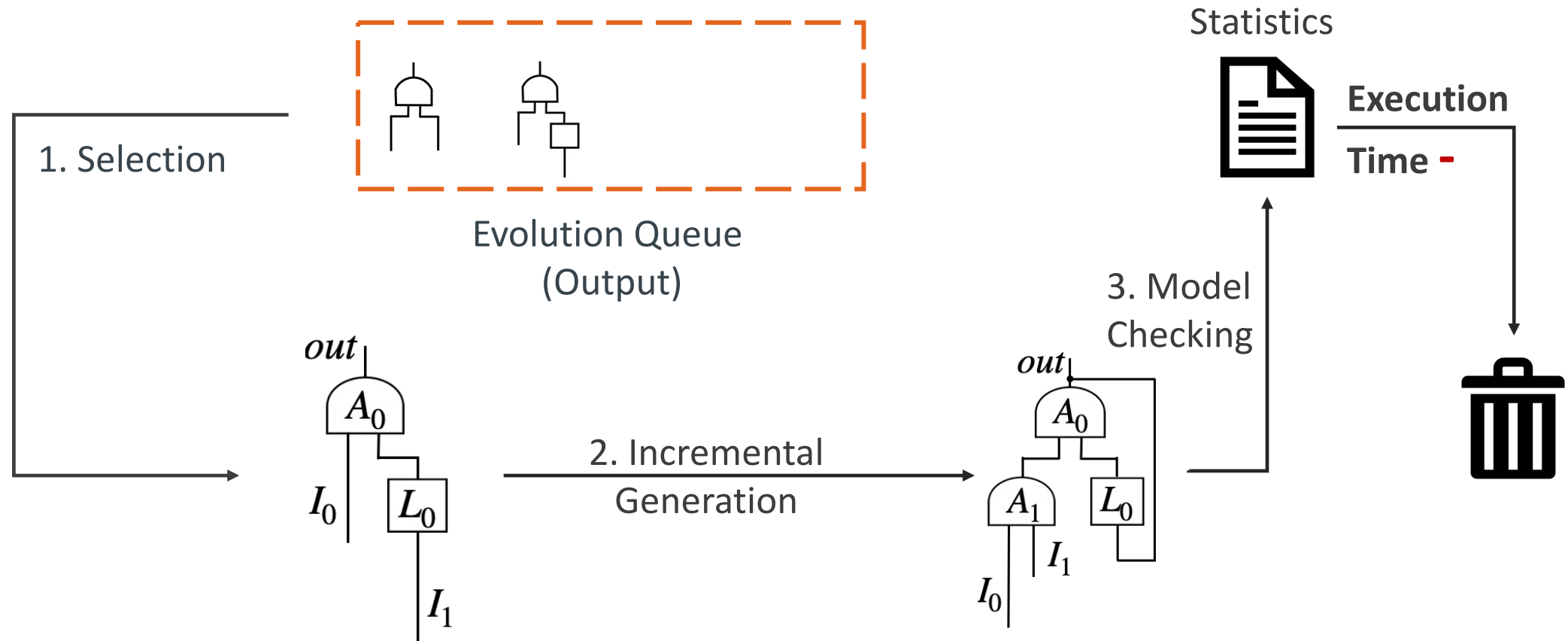
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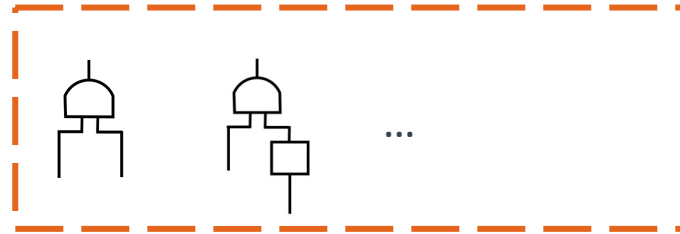
Our Feedback-Driven Framework: AIGROW



Our Feedback-Driven Framework: AIGROW



Our Feedback-Driven Framework: AIGROW



Evolution Queue
(Output)

Evaluation Setting

Testing targets

PDR: a mature hardware model checker

IC3ref: a reference implementation of IC3 algorithm

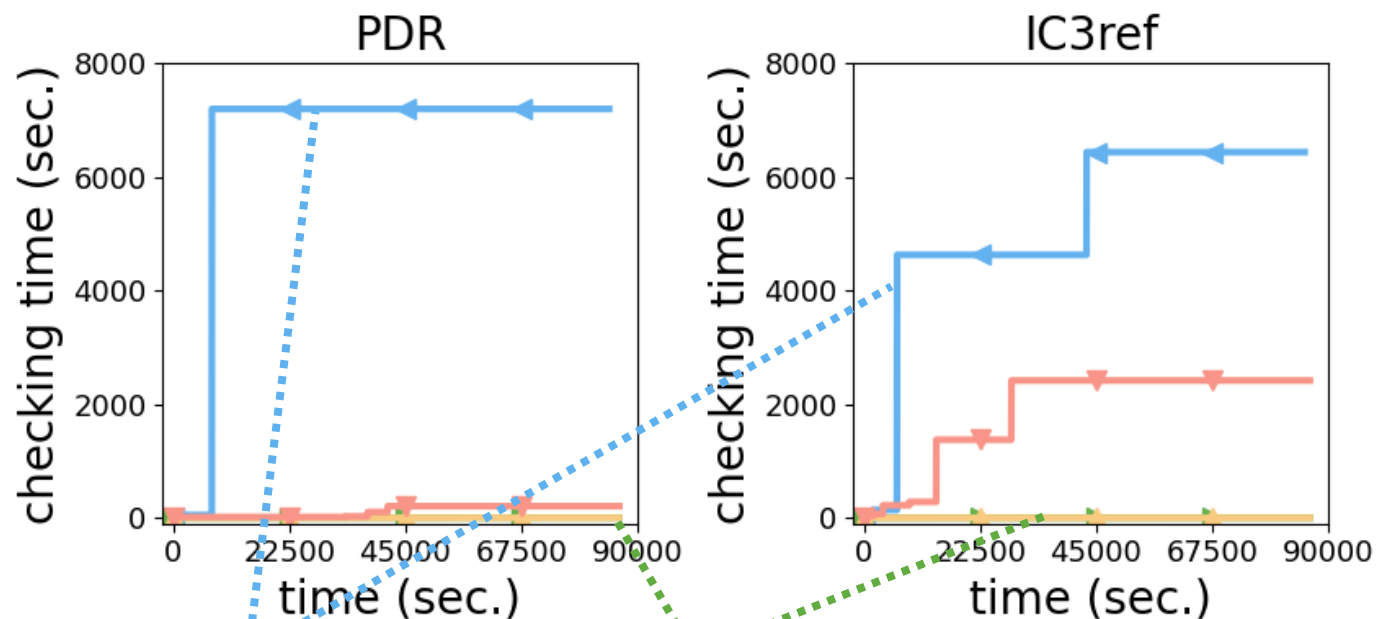
Evaluation metrics

Difficulty: checking time (sec.)

Size: #units

Diversity: line coverage (%)

Result: Difficulty



★ AIGEN ← AIGROW → AIGROW without feedback ▼ AIGFUZZ

AIGROW generates **more difficult** tests.

Feedback strategy make difference in generating difficult tests.

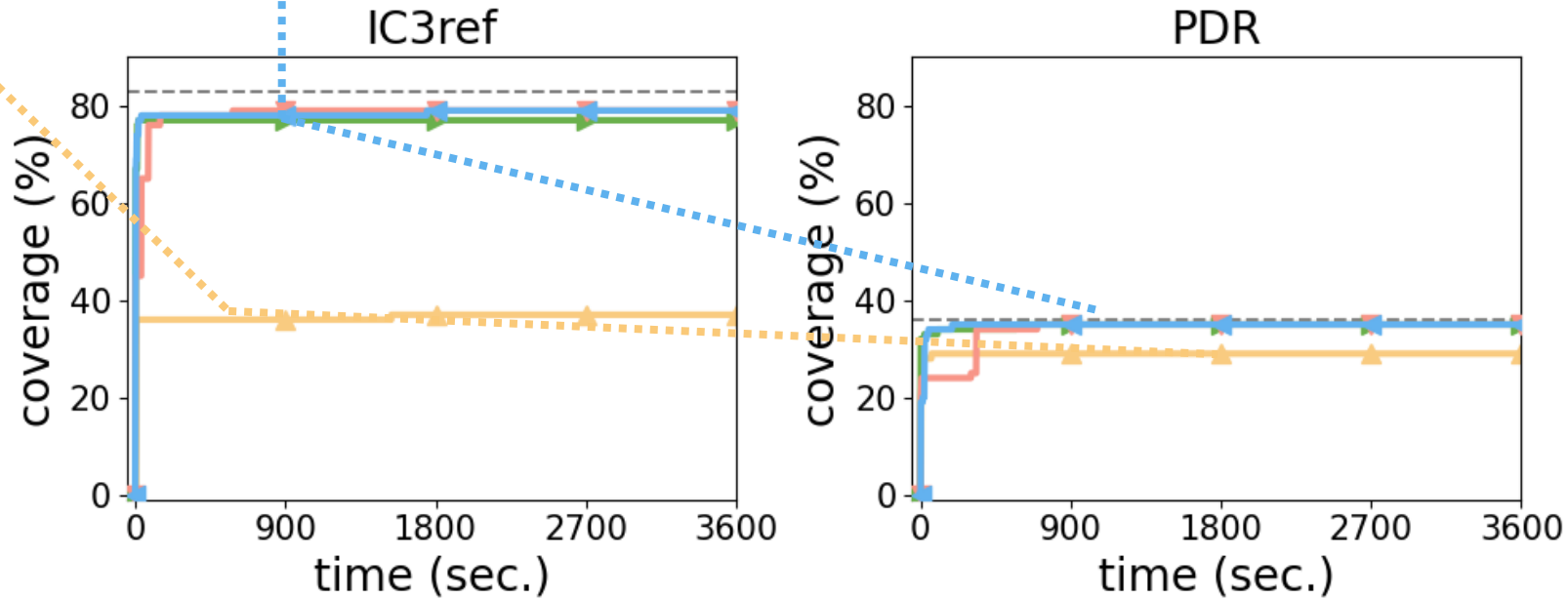
Result: Avg. Size (#units)

| Hardware Model Checker | AIGROW | AIGEN | AIGFUZZ |
|---------------------------|------------|-------|---------|
| PDR | 109 | 6,871 | 1,910 |
| IC3ref | 40 | 6,867 | 1,940 |

The avg. size of the tests generated by AIGROW is
10x smaller than AIGEN and AIGFUZZ

Result: Coverage

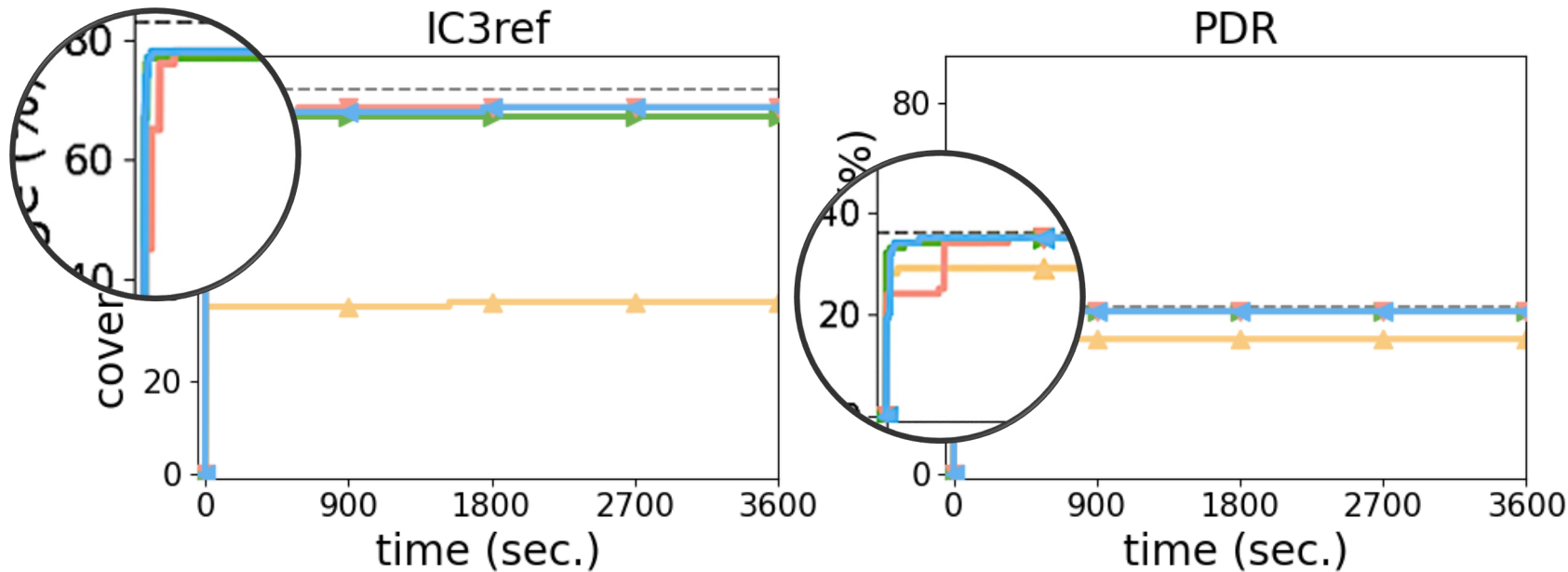
—▲— AIGEN —▶— AIGROW —▶— AIGROW without feedback —▼— AIGFUZZ



AIGROW achieves **higher coverage** than AIGEN.

Result: Coverage

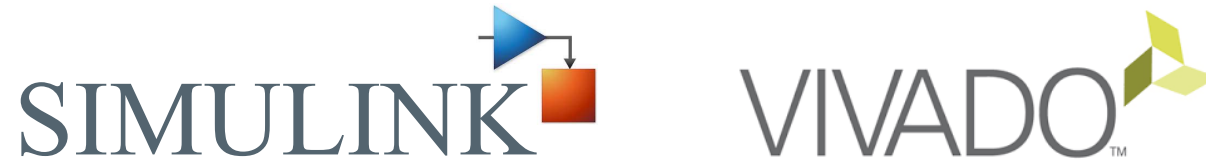
★ AIGEN ← AIGROW → AIGROW without feedback ▼ AIGFUZZ



AIGROW achieves **higher coverage** than AIGEN.
AIGROW achieves the maximum coverage **faster** than AIGFUZZ.

Future Work

- Apply this approach to test other **model-based design tools**.



- Our preliminary investigation found **21 critical bugs** in the model-based design tool of our industry partner.

Conclusion

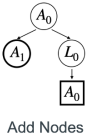
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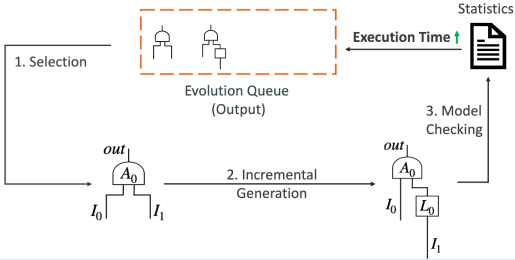
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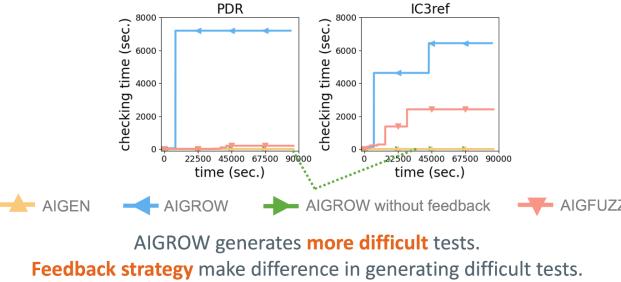
Our Approach: Incremental Generation



Our Feedback-Driven Framework: AIGROW



Result: Difficulty

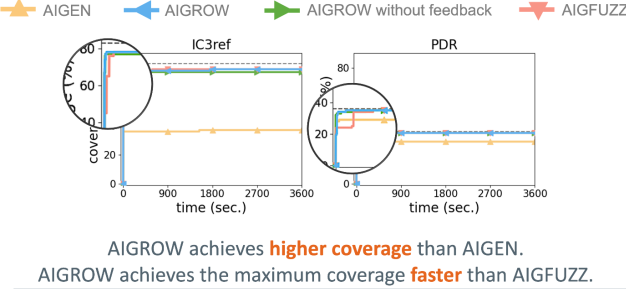


Result: Avg. Size (#units)

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Result: Coverage



Take-aways

Approach

- **Incremental generation** guided by **feedback**

Perform better than existing tools

- Generate **more difficult** test cases.
 - Achieve maximum coverage **faster**.
 - **Fewer redundant units** in a single test.
-

Introduction

Why high-quality tests are hard to obtain?

Def. High-quality Tests.

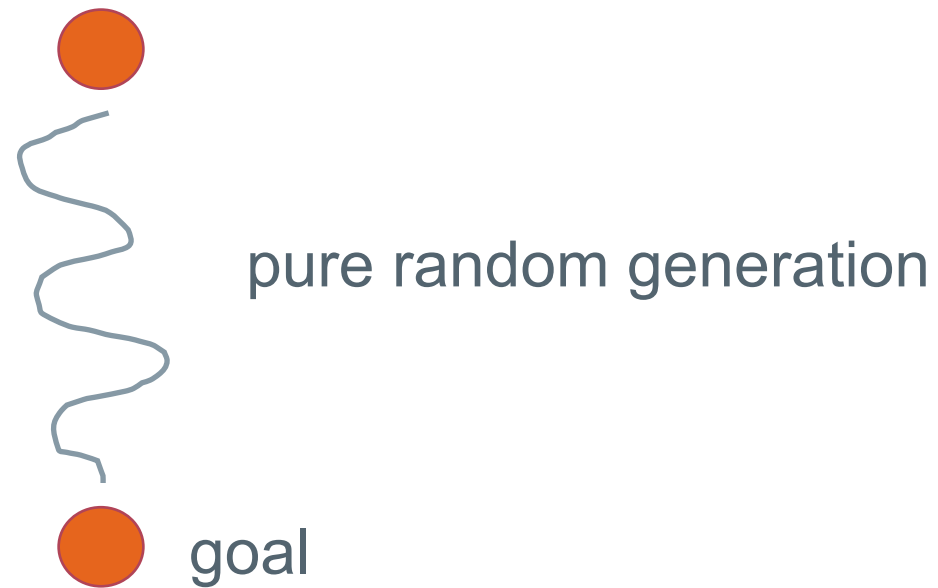
- **Hard to solve** **Evaluation**
- **Diverse** among tests **Validation**
- **Fewer redundant units** in a single test **Debug**

| Source of Tests | Always available | Fewer Redundant Units | Diverse | Hard to Solve |
|-----------------|------------------|-----------------------|---------|---------------|
| Real world | no | no | yes | yes |
| AIGEN | yes | yes | no | no |
| AIGFUZZ | yes | no | yes | no |

Our Approach avoid these shortcomings.

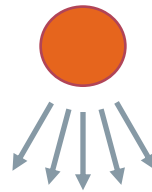
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Our Approach is to **incrementally** generate tests with **feedback**.



Approach

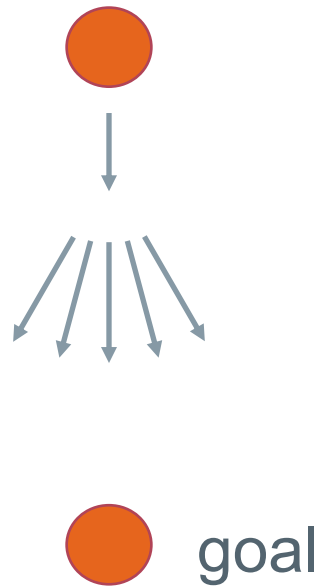
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 goal

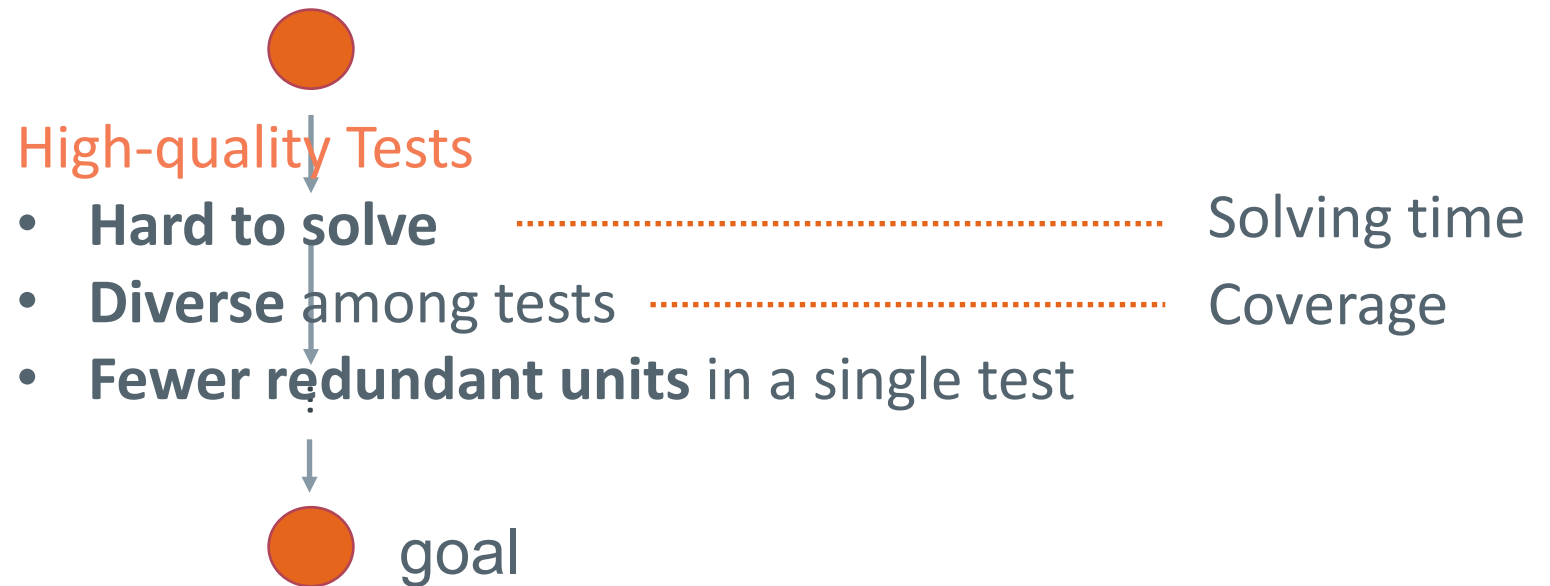
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Our Approach is to **incrementally** generate tests with **feedback**.



Layout

Background



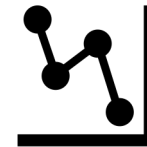
Approach



Take-away



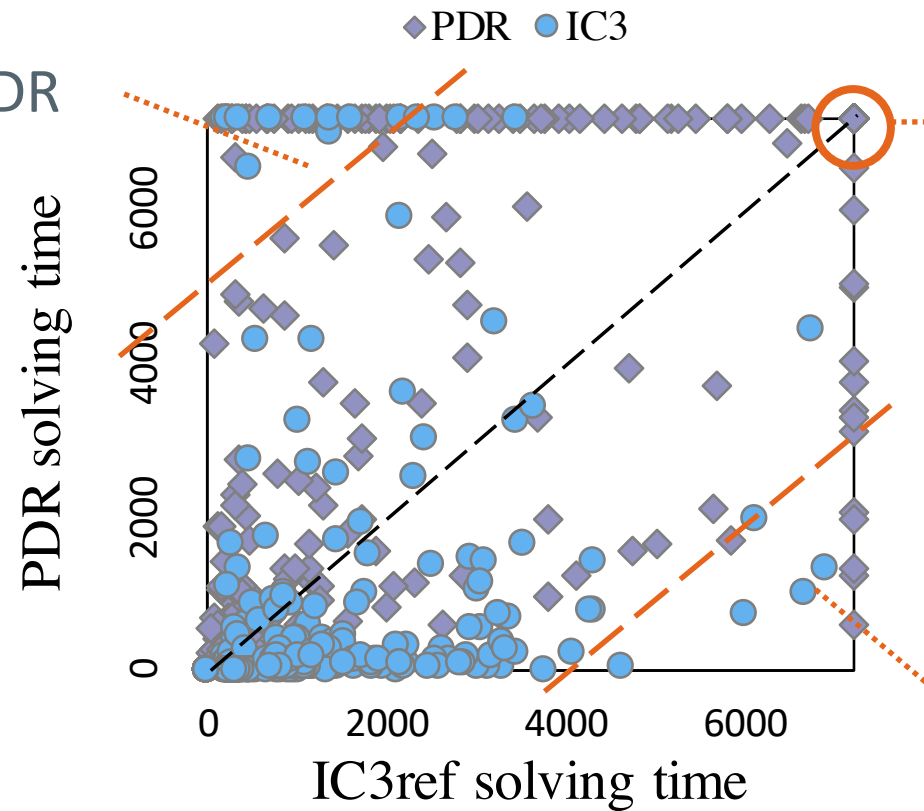
Introduction



Result

Diversity of Our Benchmarks

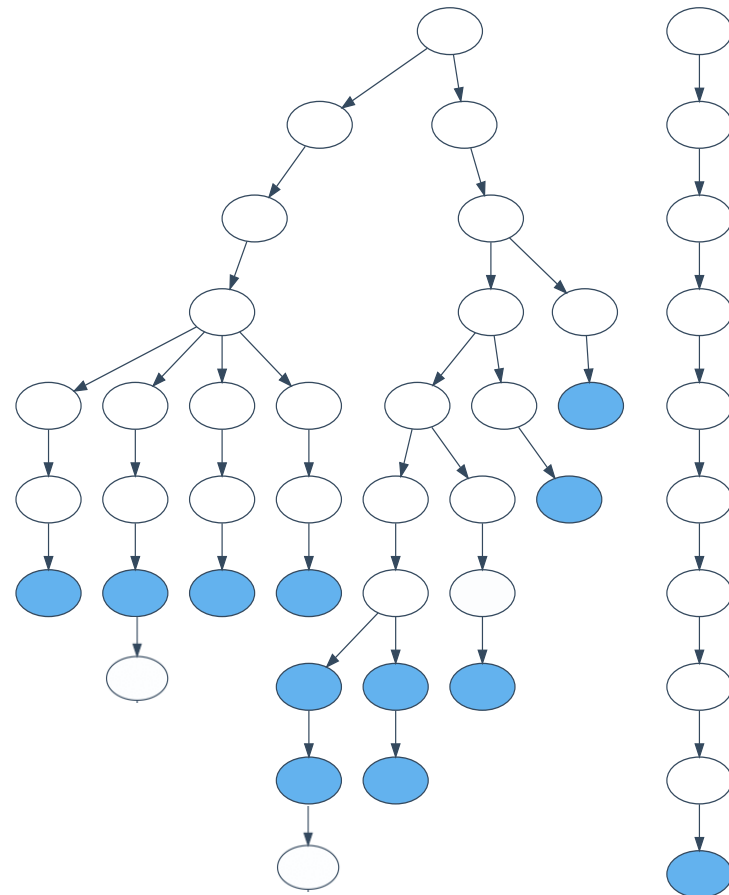
cases: IC3ref << PDR



73 cases: hard to solve for both

cases: IC3ref >> PDR

Generation Process for PDR



Background

Def. Hardware Model Checkers.

The tools for validating the implementation of hardware designs.

Hardware model checkers should be intensively validated and evaluated.



High-quality tests

hard to obtain!